

<b>Search Notes</b> 				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/623,868	COCCIA DIFERRO ET AL.	
				Examiner	Art Unit	
				SANG KIM	3654	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
559.1 242	559.1	6-23-05	SK	John Nguyen 242/597.3 597.5-.6	6-24-05	SIC
	597.1					
	597.2					
	597					
	597.4	↓	↓			
	597.3	6-24-05	SIC			
	597.5	↓	↓			
	597.6	↓	↓			
updated all above	↗	11-17-05	SIC			
wanted w/ above	↗	5-2-06	SIC			
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			